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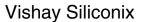
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Dual P-Channel 1.8 V (G-S) MOSFET

| PRODUCT SUMMARY | | | | |
|---------------------|--------------------------------------|--------------------|-----------------------|--|
| V _{DS} (V) | $R_{DS(on)}(\Omega)$ | I _D (A) | Q _g (Typ.) | |
| | 0.542 at $V_{GS} = -4.5 \text{ V}$ | - 0.63 | | |
| - 8 | 0.798 at V _{GS} = - 2.5 V | - 0.52 | 10.5 nC | |
| | 1.2 at V _{GS} = - 1.8 V | - 0.20 | | |

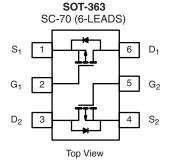
FEATURES

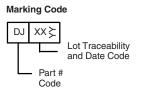
- Halogen-free According to IEC 61249-2-21 Definition
- TrenchFET® Power MOSFET
- Compliant to RoHS Directive 2002/95/EC



APPLICATIONS

· Load Switch for Portable Devices





Ordering Information: Si1905BDH-T1-E3 (Lead (Pb)-free)

Si1905BDH-T1-GE3 (Lead (Pb)-free and Halogen-free)

| ABSOLUTE MAXIMUM RATINGS $T_A = 25$ °C, unless Parameter | | Symbol | Limit | Unit | |
|---|-----------------------------------|------------------|------------------------|------|--|
| Drain-Source Voltage | | V _{DS} | - 8 | V | |
| Gate-Source Voltage | | V _{GS} | ± 8 | 7 v | |
| | T _C = 25 °C | | - 0.63 | | |
| Out in the County (T 450 00) 8 h | T _C = 70 °C | | - 0.50 | | |
| Continuous Drain Current $(T_J = 150 {}^{\circ}C)^{a, b}$ | T _A = 25 °C | I _D | - 0.58 ^{a, b} | | |
| | T _A = 70 °C | | - 0.47 ^{a, b} | А | |
| Pulsed Drain Current (10 µs Pulse Width) | | I _{DM} | - 1.8 | | |
| Continuous Source-Drain Diode Current ^{a, b} | T _C = 25 °C | 1 | - 0.30 | | |
| | T _A = 25 °C | I _S — | - 0.25 ^{a, b} | | |
| Maximum Power Dissipation ^{a, b} | T _C = 25 °C | | 0.357 | | |
| | T _C = 70 °C | В | 0.228 | | |
| | T _A = 25 °C | P _D | 0.301 ^{a, b} | W | |
| | T _A = 70 °C | | 0.193 ^{a, b} | | |
| Operating Junction and Storage Temperature Rar | T _J , T _{stg} | - 55 to 150 | 00 | | |
| Soldering Recommendations (Peak Temperature) ^{c, d} | | | 260 | °C | |

| THERMAL RESISTANCE RATINGS | | | | | |
|---|--------------|---------------------|---------|---------|------|
| Parameter | | Symbol | Typical | Maximum | Unit |
| Maniana lunation to Ambienta C | t ≤ 5 s | - R _{thJA} | 360 | 415 | °C/W |
| Maximum Junction-to-Ambient ^{a, c} | Steady State | | 400 | 460 | |
| Maximum Junction-to-Foot (Drain) | Steady State | R _{thJF} | 300 | 350 | |

Notes:

a. Surface mounted on 1" x 1" FR4 board.

b. t = 5 s.

c. Maximum under steady state conditions is 400 °C/W.

Si1905BDH

Vishay Siliconix



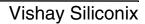
| Parameter | Symbol | Test Conditions | Min. | Тур. | Max. | Unit | |
|--|---------------------------|---|--------|----------|----------|-------|--|
| Static | | | | | | | |
| Drain-Source Breakdown Voltage | V _{DS} | $V_{GS} = 0 \text{ V}, I_D = -250 \mu\text{A}$ | - 8 | | | V | |
| V _{DS} Temperature Coefficient | $\Delta V_{DS}/T_{J}$ | L = 250 uA | | 7.15 | | mV/°C | |
| V _{GS(th)} Temperature Coefficient | $\Delta V_{GS(th)}/T_{J}$ | l _D = - 250 μA | | - 1.66 | | | |
| Gate-Source Threshold Voltage | V _{GS(th)} | $V_{DS} = V_{GS}, I_{D} = -250 \mu A$ | - 0.45 | | - 1.0 | V | |
| Gate-Source Leakage | I _{GSS} | V _{DS} = 0 V, V _{GS} = -8 V | | | - 100 | nA | |
| Zero Onto Welliams B. C. O. | I _{DSS} | V _{DS} = - 8 V, V _{GS} = 0 V | | | - 1 | μΑ | |
| Zero Gate Voltage Drain Current | | V _{DS} = -8 V, V _{GS} = 0 V, T _J = 55 °C | | | - 10 | | |
| On-State Drain Current ^a | I _{D(on)} | $V_{DS} \le 5 \text{ V}, V_{GS} = -4.5 \text{ V}$ | - 1.8 | | | Α | |
| Drain-Source On-State Resistance ^a | | V _{GS} = - 4.5 V, I _D = - 0.58 A | | 0.450 | 0.542 | Ω | |
| | R _{DS(on)} | V _{GS} = - 2.5 V, I _D = - 0.47 A | | 0.655 | 0.798 | | |
| | | V _{GS} = - 1.8 V, I _D = - 0.2 A | | 0.950 | 1.2 | | |
| Forward Transconductance ^a | 9 _{fs} | V _{DS} = - 4 V, I _D = - 0.58 A | | 1.2 | | S | |
| Dynamic ^b | | | | ' | ' | L | |
| Input Capacitance | C _{iss} | | | 62 | | pF | |
| Output Capacitance | C _{oss} | V _{DS} = - 4 V, V _{GS} = 0 V, f = 1 MHz | | 30 | | | |
| Reverse Transfer Capacitance | C _{rss} | | | 12 | | | |
| Total Gate Charge | Q_g | V _{DS} = - 4 V, V _{GS} = - 4.5 V, I _D = - 0.58 A | | 1.0 | 1.5 | nC | |
| Gate-Source Charge | Q _{qs} | | | 0.19 | | | |
| Gate-Drain Charge | Q _{gd} | | | 0.20 | | | |
| Gate Resistance | R _q | f = 1 MHz | | 6.3 | | Ω | |
| Turn-On Delay Time | t _{d(on)} | | | 9 | 14 | | |
| Rise Time | t _r | $V_{DD} = -4 \text{ V}, R_L = 8.7 \Omega$ | | 40 | 60 | - ns | |
| Turn-Off Delay Time | t _{d(off)} | $I_D \cong -0.46 \text{ A}, V_{GEN} = -4.5 \text{ V}, R_g = 1 \Omega$ | | 50 | 75 | | |
| Fall Time | t _f | | | 60 | 90 | | |
| Drain-Source Body Diode Characterist | ics | | | L | L | I | |
| Continuous Source-Drain Diode Current | I _S | T _C = 25 °C | | | - 0.30 | A | |
| Pulse Diode Forward Current | I _{SM} | | | | - 1.8 | | |
| Body Diode Voltage | V _{SD} | I _S = - 1.4 A, V _{GS} = 0 V | | - 0.8 | - 1.2 | V | |
| Body Diode Reverse Recovery Time t _{rr} | | | | 25 | 38 | ns | |
| Body Diode Reverse Recovery Charge | Q _{rr} | I _F = - 1.4 A, dl/dt = 100 A/μs, T _J = 25 °C | | 7 | 11 | nC | |
| Reverse Recovery Fall Time | t _a | | | 9 | | ns | |
| Reverse Recovery Rise Time | t _b | | | 16 | | | |

Notes:

- a. Pulse test; pulse width \leq 300 μ s, duty cycle \leq 2 %. b. Guaranteed by design, not subject to production testing.

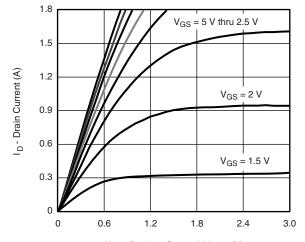
Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.





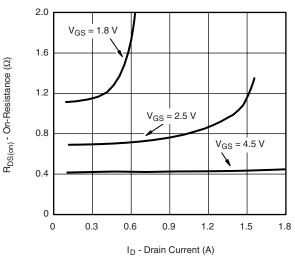


TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

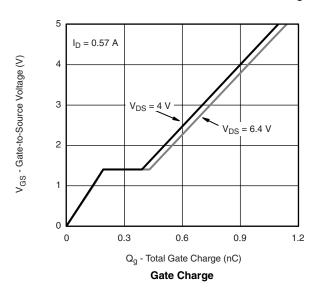


V_{DS} - Drain-to-Source Voltage (V)

Output Characteristics

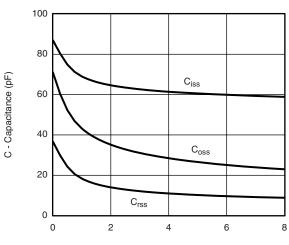


On-Resistance vs. Drain Current and Gate Voltage



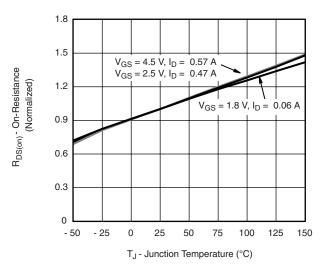
0.5 0.4 0.4 (Y) to a purple of the purple

V_{GS} - Gate-to-Source Voltage (V) **Transfer Characteristics**



V_{DS} - Drain-to-Source Voltage (V)

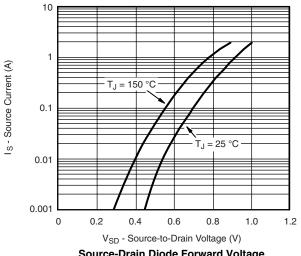
Capacitance

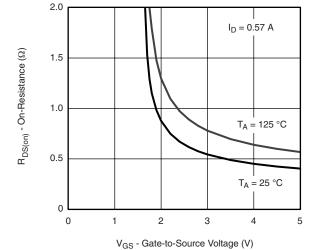


On-Resistance vs. Junction Temperature

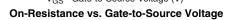
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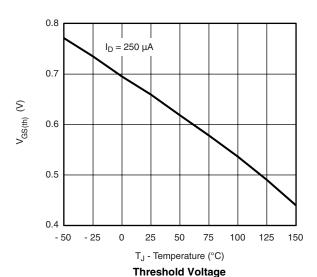
TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

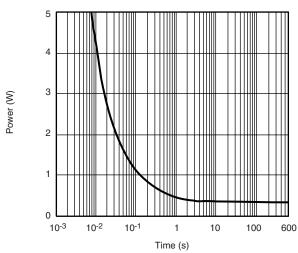




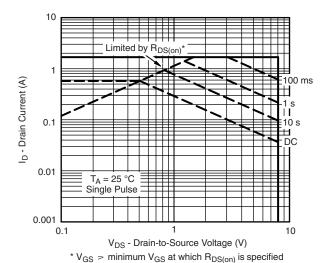
Source-Drain Diode Forward Voltage







Single Pulse Power, Junction-to-Ambient



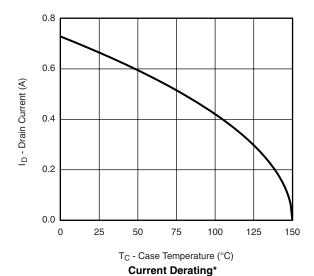
Safe Operating Area, Junction-to-Ambient

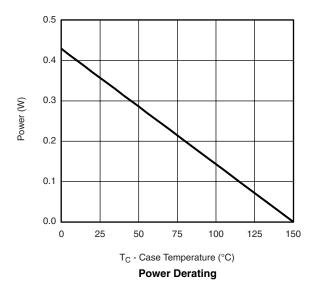






TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



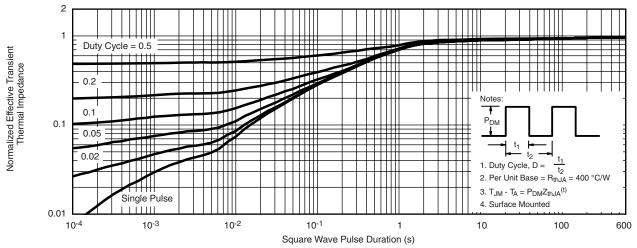


^{*} The power dissipation P_D is based on $T_{J(max)} = 150$ °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.

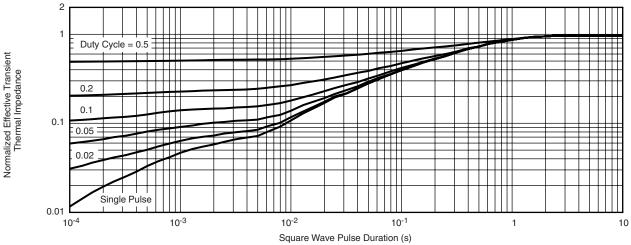
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TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



Normalized Thermal Transient Impedance, Junction-to-Ambient



Normalized Thermal Transient Impedance, Junction-to-Case

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